查询MB47393供应商

FUJITSU SEMICONDUCTOR DATA SHEET

DS04-12103-4E

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ASSP

DUAL COMPARATOR

MB47393

DESCRIPTION

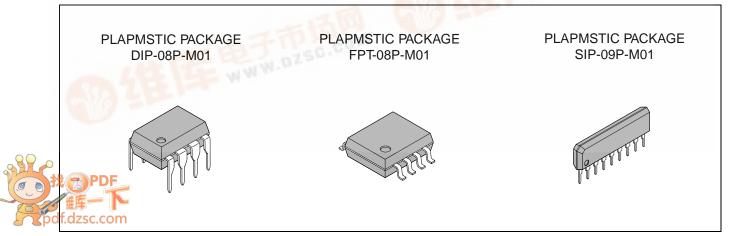
The Fujitsu MB47393 is a dual comparator which is designed to operate from a single power supply over a wide range of voltage. The input characteristics is equivalent of current industry standard comparator. Even though operated from a single power supply, the input common mode voltage range includes ground. Owing to adoption of clamp circuitry in input pins, mis-operation is prevented by negative input. The MB47393 is compatible with LM393.

FEATURES

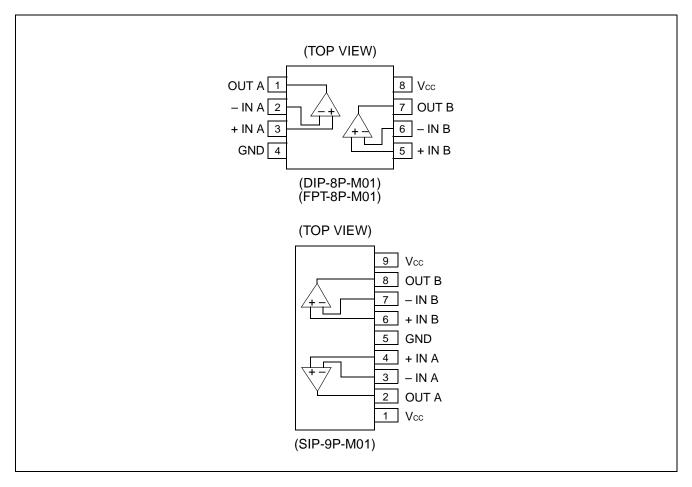
- Wide power supply voltage range Single power supply — 2V to 30V Dual power supplies — ±1V to ±15V
- Wide input common-mode voltage range 0V to (Vcc – 1.5)V
- Low input bias current 25nA typ.
- High sink current capability because of open collector output 40mA min.
- Package

| Plastic 8 pin DIP package | (Suffix: –P) |
|---------------------------|---------------|
| Plastic 8 pin FPT package | (Suffix: –PF) |
| Plastic 9 pin SIP package | (Suffix: –PS) |

PACKAGE



■ PIN ASSIGNMENT



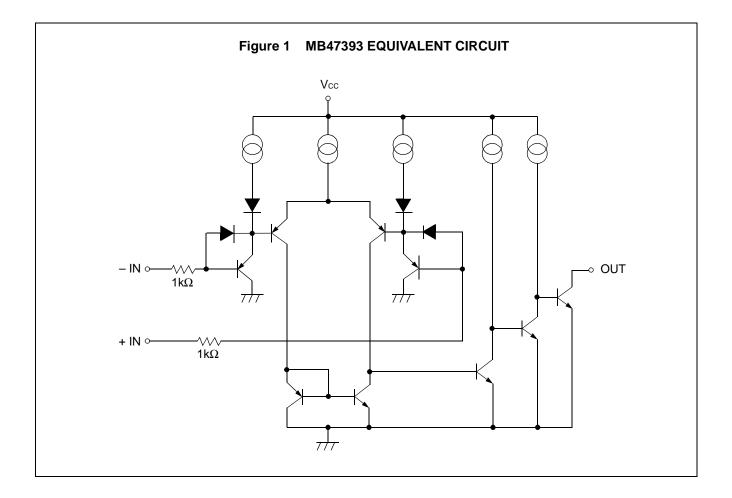
■ ABSOLUTE MAXIMUM RATINGS (see NOTE)

Ta = 25°C

| Rating | Symbol | Value | Unit |
|-----------------------------|--------|---------------|------|
| Power Supply Voltage | Vcc | 36 | V |
| Differential Input Voltage | VID | 36 | V |
| Common-Mode Input Voltage | VI | -5 to +36 | V |
| Output Short Current to GND | | Infinite* | |
| Power Dissipation | PD | 350 (Ta 55°C) | mW |
| Operating Temperature | Та | -20 to +75 | °C |
| Storage Temperature | Тѕтс | -55 to +125 | °C |

* : This value is specified with respect to the short circuit from output to GND. However, short circuit from the output to Vcc cause device destruction.

Note: Permanent device damage may occur if the above Absolute Maximum Ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



■ RECOMMENDED OPERATING CONDITIONS

| Parameter | Symbol | Value | Unit |
|-----------------------|--------|-------------|------|
| Power Supply Voltage | Vcc | 2 to 30 | V |
| | | ±1.0 to ±15 | V |
| Operating Temperature | Та | -20 to +75 | °C |
| Output Sink Current | Isink | 40 | mA |

ELECTRICAL CHARACTERISTICS

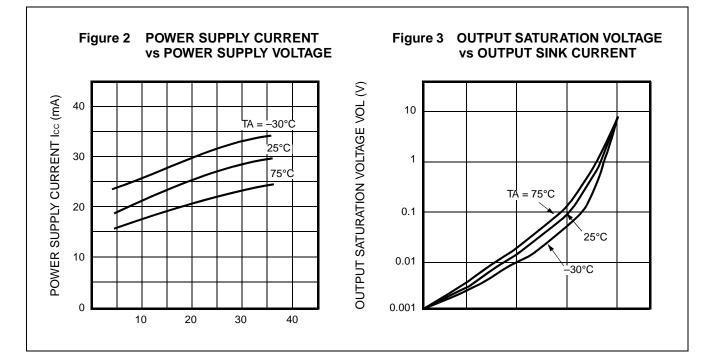
 $(Ta = 25^{\circ}C, Vcc = 5V)$

| Parameter | Symbol | Condition | Value | | | Unit |
|---------------------------|--------|---|-------|------|---------|------|
| | | | Min. | Тур. | Max. | Unit |
| Input Offset Voltage | Vio | $V_0 = V_{REF} = 1.4V$ | | 2 | 5 | mV |
| Input Offset Current | lio | _ | | 5 | 50 | nA |
| Input Bias Current | IIN*1 | _ | | 25 | 250 | nA |
| Common-Mode Input Voltage | Vcm*2 | _ | 0 | | Vcc-1.5 | V |
| Power Supply Current | Icc | R∟ = ∞ | | 2 | 3 | mA |
| Voltage Gain | Av | R∟ = 15kΩ, Vcc = 15V | | 200 | | V/mV |
| Response Time | | R∟ = 1kΩ | | 2 | | μs |
| Output Sink Current | Isink | $V_{IN(+)} = 0, V_{IN(-)} = 1V, V_{OL} \ \delta \ 1.5V$ | 40 | | | mA |
| Output Saturation Voltage | Vol | $V_{IN(+)} = 0, V_{IN(-)} = 1V, I_{SINK} = 30mA$ | | 0.2 | 0.4 | V |
| Output Leakage Current | ILEAK | $V_{IN(+)} = 1V, V_{IN(-)} = 0V, V_0 = 30V$ | | | 1 | μA |

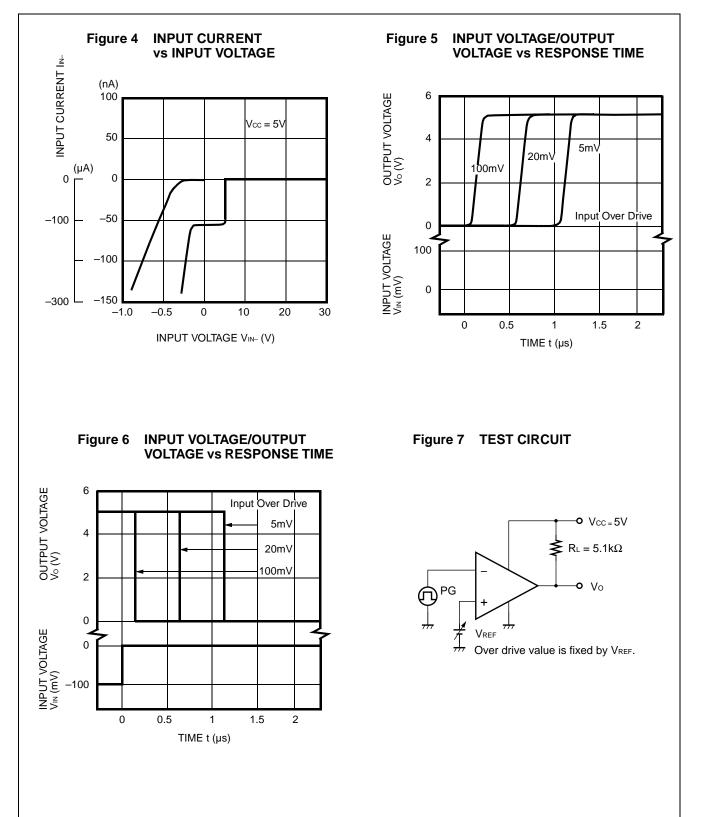
Notes:

- *1: I_{IN} is measured when V_I Š 0 and direction of the input current flows from IC. When negative voltage is applied to input pin, the pin is equivalently connected the GND through a 1kΩ of resistor. When low voltage below than –5V is applied, please connect a resistor serially to input pin in order to prevent the high current flow.
- *2: Positive input voltage may exceed the power supply voltage. As long as the other voltage remains in the commonmode input voltage range, the comparator will provide a proper output state. When V_{cc} = 5V, your are requested to use V_{IN} below 25V.

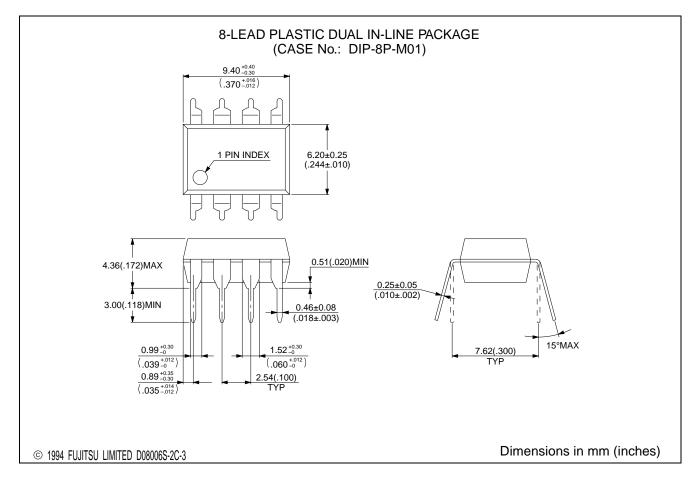
■ TYPICAL CHARACTERISTIC CURVES



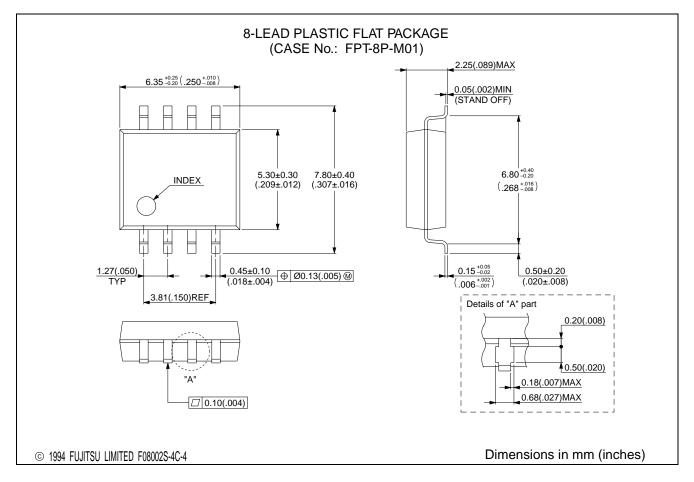
■ TYPICAL CHARACTERISTIC CURVES (Continued)



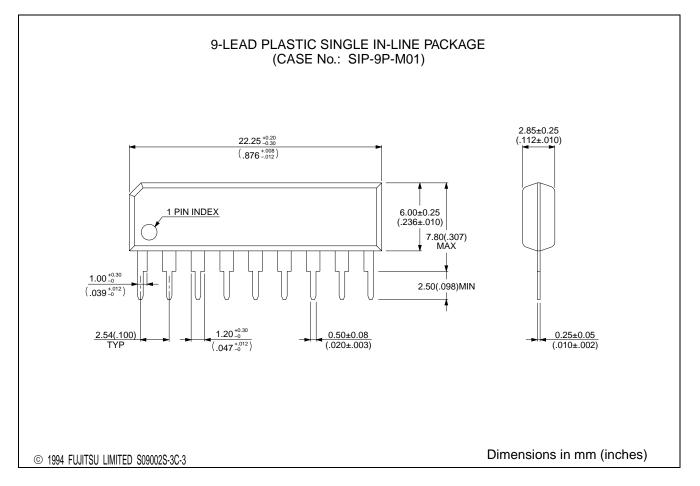
■ PACKAGE DIMENSIONS



■ PACKAGE DIMENSIONS (Continued)



■ PACKAGE DIMENSIONS (Continued)



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